# Neutron damage and trapping effects

•Why this talk?

- •Trapping cross sections
- •A little theory
- •Detector "sensitivity" to trapping
- •Correction of trapping:
- detectors w/o damageneutron damaged detectorsConclusion & ideas for the future
- Analysis by A. Wiens & D. Bazzacco

Bart Bruyneel, Andreas Wiens, Dino Bazzacco for the AGATA collaboration – 10<sup>th</sup> AGATA week Lyon, 22-26nov 2010

# Why this talk?

### <u>AGATA</u>

. . .

- Large volume detector: large radius = higher sensitivity for trapping
- Segments more sensitive to neutron damage than core (n-type)
- High count rate capability ("Yes, we can...")
- High efficiency ... also for neutrons ...





### Det. 1B - Shape of the 1332 keV line





White: April 2010  $\rightarrow$  FWHM(core) ~ **2.3 keV** FWHM(segments) ~**2.0 keV** Green: July 2010  $\rightarrow$  FWHM(core) ~**2.4 keV** FWHM(segments) ~**2.8 keV** Damage after 3 high-rate experiments (3 weeks of beam at 30-80 kHz singles)

Worsening seen in most of the detectors; more severe on the forward crystals; segments are the most affected, cores almost unchanged (as expected for n-type HPGe)

# Crystal 1B (COO2) April 2010 July 2010







The 1332 keV peak as a function of crystal depth (z) for interactions at r = 15mm

The charge loss due to neutron damage is proportional to the path length to the electrodes. This is provided by the PSA, which is barely affected by the amplitude loss.

Knowing the interaction position, the charge trapping can be modeled and corrected away

# Trapping cross sections

L. Reggiani – Rev. del Nuovo Cimento 12 nr 11 (1989)

Most popular is model by Lax: Cross sections are **velocity** dependent

Cross sections are **field dependent** - e.g. Poole – Frenkel effect



### Trapping cross section: neutron damage specific

L. S. Darken et al. NIM 171 (1980)



#### Specific model for fast neutron induced traps:



#### Cross section from field line disturbance:

Balance between E field and Coulomb force:



#### Assumptions:

- Trapping only by disordered regions
  Macroscopic model: drift velocity!
- $Q \sim 100e$  equilibrium charge state
- $r_{max}$ ~ 2 µm cross section (E=2kV/cm)
- $I_e \sim 0.2 \; \mu m \,$  dist. betw. optical phonon emission



# Some theory: collection efficiency

T.W. Raudorf, R. H. Pehl – NIM A 255 (1987) 538-551

•Trapping rate of electrons / holes "q":

$$\frac{dq}{dt} = - \langle \sigma v \rangle N_t q \quad \Leftrightarrow \quad q(t) = q_0 \cdot e^{-\int_0^t \langle \sigma v \rangle N_t dt'}$$

- $\boldsymbol{\sigma}$  : trapping cross section
- v : microscopic velocity
- <.>: average over ensemble
- N<sub>t</sub> : density of trapping centers

•Collection efficiency (position dependent) of electrons / holes for electrode "i":

$$\eta_{e,h}^{i}(\vec{x}_{0}) = -\int_{0}^{t_{e}} \left(\vec{\nabla}\phi_{i}\cdot\vec{v}_{e,h}\right) \cdot \frac{q(t)}{q_{0}} dt$$

- $\mathbf{x}_0$  : interaction position in detector
- $\varphi_i \;$  : weighting potential of segment i
- v<sub>e,h</sub> : drift velocity of electrons / holes
- $\mathbf{t}_{\mathbf{e}}~$  : collection time
- Integral [ current to seg i per unit charge ]
- = total recorded charge by e/h after collection

•Total collection efficiency for electrode "i" at position x<sub>0</sub>:

$$\eta_{tot}^{i}(\vec{x}_{0}) = \eta_{e}^{i}(\vec{x}_{0}) + \eta_{h}^{i}(\vec{x}_{0})$$

$$\downarrow \qquad \searrow$$

$$\simeq \phi_{i}(\vec{x}_{0}) + [1 - \phi_{i}(\vec{x}_{0})] \cong 1$$

Partial collection efficiencies mainly report on weighting potential

# Trapping sensitivity\*

(\*personal definition – don't google!)

•DEFINITION: electron / hole sensitivity of electrode i to trapping

$$s_{e,h}^i = \frac{d\eta_{e,h}^i}{dN_t} \mid_{N_t=0}$$

= fraction missing due to trapping

+ induced charge due to trail of trapped charges

•Relation to total collection efficiency:

$$\eta_{tot}^{i}(\vec{x}_{0}) = 1 + \left[ N_{e} s_{e}^{i}(\vec{x}_{0}) + N_{h} s_{h}^{i}(\vec{x}_{0}) \right] + O(2)$$

- •Ne : density of electron traps, Nh: density of hole traps
- •O(2) higher order terms in taylor expansion negligible
- •sensitivities can be calculated in advance
- •Ne, Nh are fit parameters









1330└ 5

10

15

20

25

radius [mm]

30

35

40

## Trapping in <u>new</u> detectors

#### (A. Wiens)

•Electron trapping present in any detector •Source of scattering on Fano factors



### Correction of neutron damage









## Correction of neutron damage

$$\eta_{tot}^{i}(\vec{x}_{0}) = 1 + \left[ N_{e} s_{e}^{i}(\vec{x}_{0}) + N_{h} s_{h}^{i}(\vec{x}_{0}) \right]$$



# The 1332 keV peak as a function of crystal depth (z) for interactions at r = 15mm (worst case !)



### Conclusion & ideas for the future

•AGATA : best data ever to investigate trapping!

- •Neutron damage confirms PSA principle (and PSA works also in neutron damaged detectors)
- •First results promising with simple assumptions
   →simple 2 parameter fit
- •N<sub>t</sub> assumed homogeneous in detector
   →CV measurement for determination of trap distributions?
- •"grilling" less effective near core?
  →Equilibrium charge states of traps vs position?
- •Better descriptions  $<\sigma v > \propto E^x < v^y >$  ?
- ●Field dependence investigation
  → Investigations as function of bias voltage?





